



Integrated Device Technology, Inc.

# FAST CMOS 8-BIT IDENTITY COMPARATOR

**IDT54/74FCT521T**  
**IDT54/74FCT521AT**  
**IDT54/74FCT521BT**  
**IDT54/74FCT521CT**

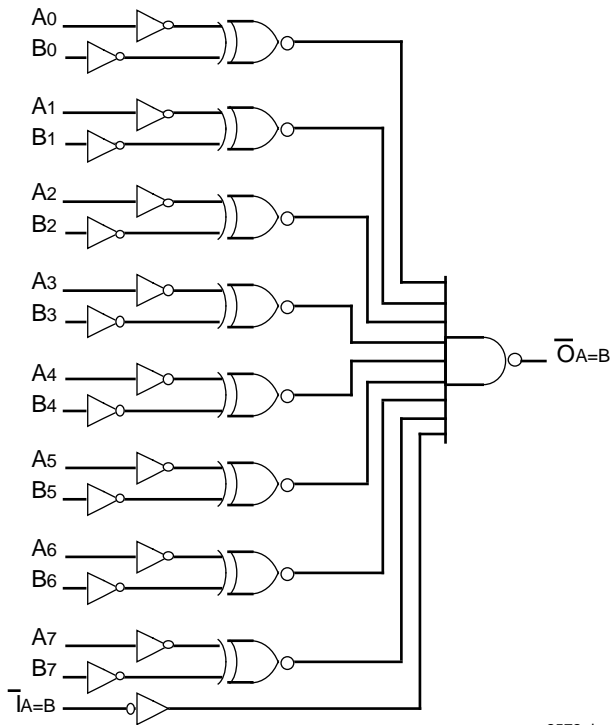
## FEATURES:

- Std., A, B and C speed grades
- Low input and output leakage  $\leq 1\mu\text{A}$  (max.)
- CMOS power levels
- True TTL input and output compatibility
  - $V_{OH} = 3.3\text{V}$  (typ.)
  - $V_{OL} = 0.3\text{V}$  (typ.)
- High drive outputs (-15mA  $I_{OH}$ , 48mA  $I_{OL}$ )
- Meets or exceeds JEDEC standard 18 specifications
- Product available in Radiation Tolerant and Radiation Enhanced versions
- Military product compliant to MIL-STD-883, Class B and DESC listed (dual marked)
- Available in DIP, SOIC, SSOP, QSOP, CERPACK and LCC packages

## DESCRIPTION:

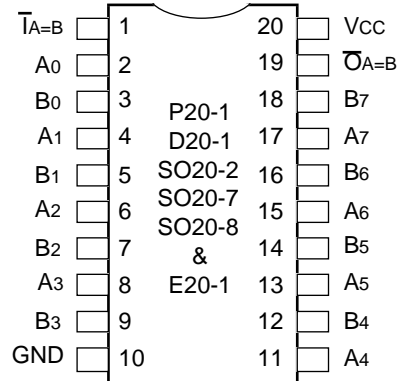
The IDT54/74FCT521T/AT/BT/CT are 8-bit identity comparators built using an advanced dual metal CMOS technology. These devices compare two words of up to eight bits each and provide a LOW output when the two words match bit for bit. The expansion input  $\bar{I}_A = B$  also serves as an active LOW enable input.

## FUNCTIONAL BLOCK DIAGRAM



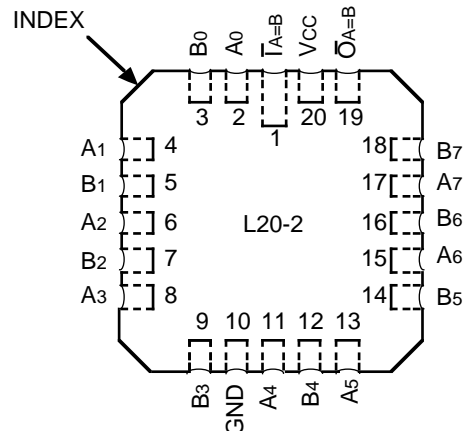
2572 drw 01

## PIN CONFIGURATIONS



**DIP/SOIC/SSOP/QSOP/CERPACK  
TOP VIEW**

2572 drw 02



**LCC  
TOP VIEW**

2572 drw 03

The IDT logo is a registered trademark of Integrated Device Technology, Inc.

**MILITARY AND COMMERCIAL TEMPERATURE RANGES**

**APRIL 1995**

## PIN DESCRIPTION

Pin Names	Description
A <sub>0</sub> - A <sub>7</sub>	Word A Inputs
B <sub>0</sub> - B <sub>7</sub>	Word B Inputs
$\bar{I}_{A=B}$	Expansion or Enable Input (Active LOW)
$\bar{O}_{A=B}$	Identity Output (Active LOW)

2572 tbl 01

## FUNCTION TABLE<sup>(1)</sup>

Inputs		Output
$\bar{I}_{A=B}$	A, B	$\bar{O}_{A=B}$
L	A = B*	L
L	A ≠ B	H
H	A = B*	H
H	A ≠ B	H

### NOTE:

1. H = HIGH Voltage Level  
L = LOW Voltage Level  
\*A<sub>0</sub> = B<sub>0</sub>, A<sub>1</sub> = B<sub>1</sub>, A<sub>2</sub> = B<sub>2</sub>, etc.

2572 tbl 02

## CAPACITANCE (T<sub>A</sub> = +25°C, f = 1.0MHz)

Symbol	Parameter <sup>(1)</sup>	Conditions	Typ.	Max.	Unit
C <sub>IN</sub>	Input Capacitance	V <sub>IN</sub> = 0V	6	10	pF
C <sub>OUT</sub>	Output Capacitance	V <sub>OUT</sub> = 0V	8	12	pF

### NOTE:

1. This parameter is measured at characterization but not tested.

2572 lnk 04

## DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Commercial: T<sub>A</sub> = 0°C to +70°C, V<sub>CC</sub> = 5.0V ± 5%; Military: T<sub>A</sub> = -55°C to +125°C, V<sub>CC</sub> = 5.0V ± 10%

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
V <sub>IH</sub>	Input HIGH Level	Guaranteed Logic HIGH Level		2.0	—	—	V
V <sub>IL</sub>	Input LOW Level	Guaranteed Logic LOW Level		—	—	0.8	V
I <sub>IH</sub>	Input HIGH Current <sup>(4)</sup>	V <sub>CC</sub> = Max.	V <sub>I</sub> = 2.7V	—	—	±1	μA
I <sub>IL</sub>	Input LOW Current <sup>(4)</sup>	V <sub>CC</sub> = Max.	V <sub>I</sub> = 0.5V	—	—	±1	μA
I <sub>I</sub>	Input HIGH Current <sup>(4)</sup>	V <sub>CC</sub> = Max., V <sub>I</sub> = V <sub>CC</sub> (Max.)		—	—	±1	μA
V <sub>IK</sub>	Clamp Diode Voltage	V <sub>CC</sub> = Min., I <sub>N</sub> = -18mA		—	-0.7	-1.2	V
I <sub>OS</sub>	Short Circuit Current	V <sub>CC</sub> = Max. <sup>(3)</sup> , V <sub>O</sub> = GND		-60	-120	-225	mA
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min. V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -6mA MIL. I <sub>OH</sub> = -8mA COM'L.	2.4	3.3	—	V
			I <sub>OH</sub> = -12mA MIL. I <sub>OH</sub> = -15mA COM'L.	2.0	3.0	—	V
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min. V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 32mA MIL. I <sub>OL</sub> = 48mA COM'L.	—	0.3	0.5	V
V <sub>H</sub>	Input Hysteresis	—		—	200	—	mV
I <sub>CC</sub>	Quiescent Power Supply Current	V <sub>CC</sub> = Max. V <sub>IN</sub> = GND or V <sub>CC</sub>		—	0.01	1	mA

### NOTES:

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at V<sub>CC</sub> = 5.0V, +25°C ambient.
- Not more than one output should be shorted at one time. Duration of the short circuit test should not exceed one second.
- The test limit for this parameter is ±5μA at T<sub>A</sub> = -55°C.

2572 tbl 05

**POWER SUPPLY CHARACTERISTICS**

Symbol	Parameter	Test Conditions <sup>(1)</sup>		Min.	Typ. <sup>(2)</sup>	Max.	Unit
$\Delta I_{CC}$	Quiescent Power Supply Current TTL Inputs HIGH	$V_{CC} = \text{Max.}$ $V_{IN} = 3.4V^{(3)}$		—	0.5	2.0	mA
$I_{CCD}$	Dynamic Power Supply Current <sup>(4)</sup>	$V_{CC} = \text{Max.}$ Outputs Open One Input Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = GND$	—	0.15	0.25	mA/ MHz
$I_C$	Total Power Supply Current <sup>(5)</sup>	$V_{CC} = \text{Max.}$ Outputs Open $f_i = 10\text{MHz}$ One Bit Toggling 50% Duty Cycle	$V_{IN} = V_{CC}$ $V_{IN} = GND$	—	1.5	3.5	mA
			$V_{IN} = 3.4V$ $V_{IN} = GND$	—	1.8	4.5	

2572 tbl 06

**NOTES:**

- For conditions shown as Max. or Min., use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at  $V_{CC} = 5.0V$ ,  $+25^\circ\text{C}$  ambient.
- Per TTL driven input ( $V_{IN} = 3.4V$ ). All other inputs at  $V_{CC}$  or  $GND$ .
- This parameter is not directly testable, but is derived for use in Total Power Supply Calculations.
- Values for these conditions are examples of the  $I_{CC}$  formula. These limits are guaranteed but not tested.
- $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$   
 $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD} (f_{CP}/2 + f_i N_i)$   
 $I_{CC}$  = Quiescent Current  
 $\Delta I_{CC}$  = Power Supply Current for a TTL High Input ( $V_{IN} = 3.4V$ )  
 $D_H$  = Duty Cycle for TTL Inputs High  
 $N_T$  = Number of TTL Inputs at  $D_H$   
 $I_{CCD}$  = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)  
 $f_{CP}$  = Clock Frequency for Register Devices (Zero for Non-Register Devices)  
 $f_i$  = Input Frequency  
 $N_i$  = Number of Inputs at  $f_i$   
 All currents are in milliamps and all frequencies are in megahertz.

**SWITCHING CHARACTERISTICS OVER OPERATING RANGE**

Symbol	Parameter	Condition <sup>(1)</sup>	IDT54/74FCT521T		IDT54/74FCT521AT		IDT54/74FCT521BT		IDT54/74FCT521CT		Unit								
			Com'l.		Mil.		Com'l.		Mil.			Com'l.		Mil.					
			Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.		Min. <sup>(2)</sup>	Max.	Min. <sup>(2)</sup>	Max.				
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay An or Bn to $\overline{O}_A = B$	CL = 50pF RL = 500Ω	1.5	11.0	1.5	15.0	1.5	7.2	1.5	9.5	1.5	5.5	1.5	7.3	1.5	4.5	1.5	5.1	ns
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay $\overline{I}_A = B$ to $\overline{O}_A = B$		1.5	10.0	1.5	9.0	1.5	6.0	1.5	7.8	1.5	4.6	1.5	6.0	1.5	4.1	1.5	4.5	ns

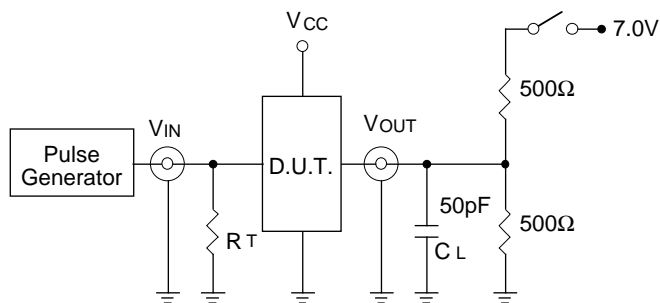
2572 tbl 07

**NOTES:**

- See test circuit and waveforms.
- Minimum limits are guaranteed but not tested on Propagation Delays.

## TEST CIRCUITS AND WAVEFORMS

### TEST CIRCUITS FOR ALL OUTPUTS



2572 drw 04

### SWITCH POSITION

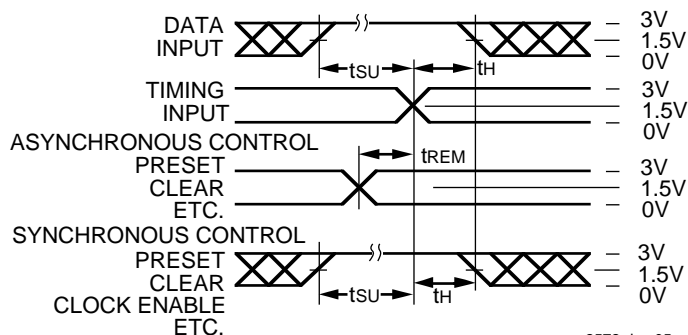
Test	Switch
Open Drain Disable Low Enable Low	Closed
All Other Tests	Open

#### DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.  
RT = Termination resistance: should be equal to ZOUT of the Pulse Generator.

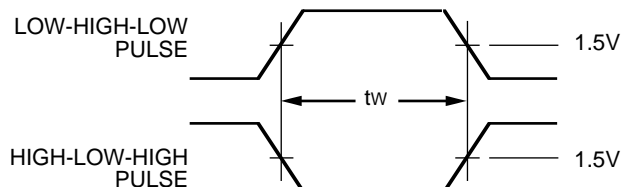
2572 Ink 08

### SET-UP, HOLD AND RELEASE TIMES



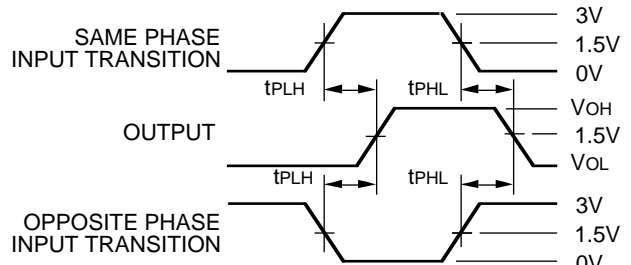
2572 drw 05

### PULSE WIDTH



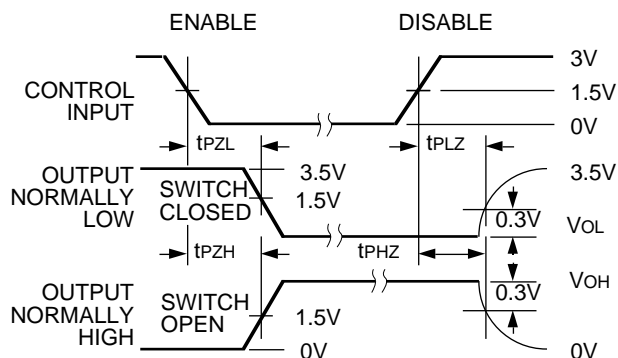
2572 drw 06

### PROPAGATION DELAY



2572 drw 07

### ENABLE AND DISABLE TIMES

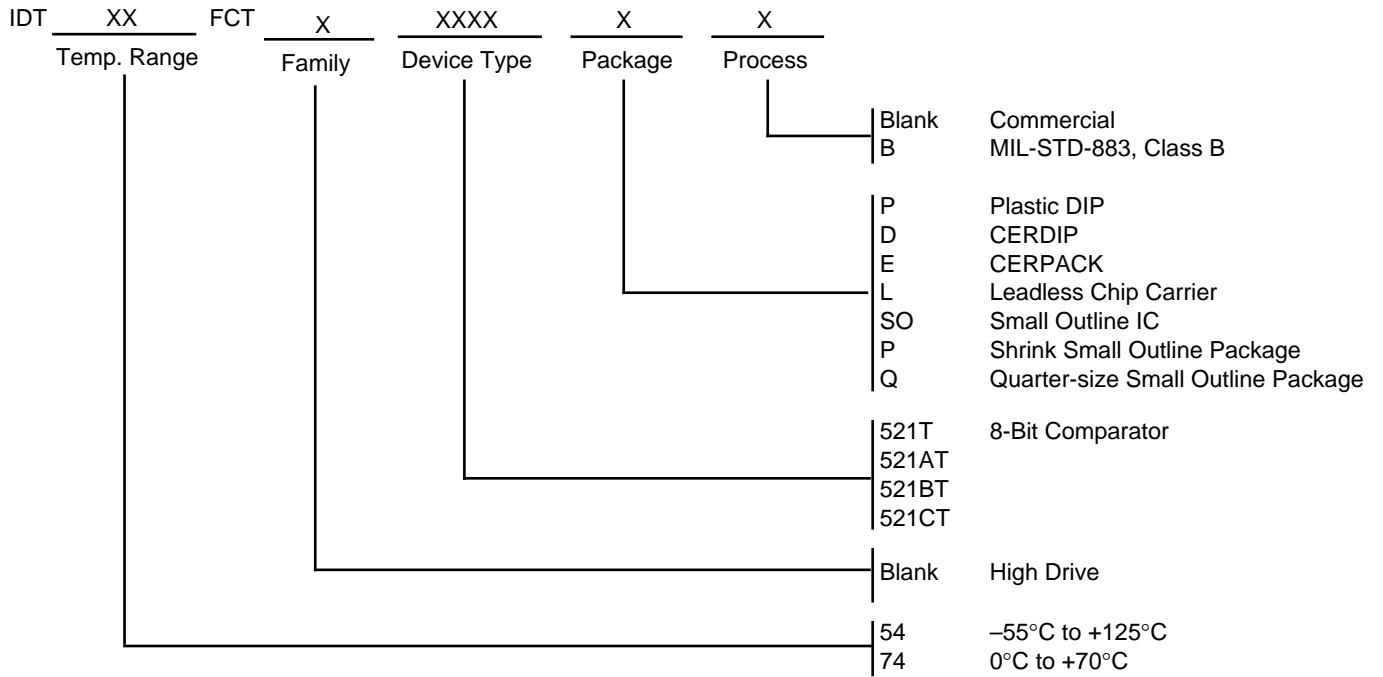


2572 drw 08

#### NOTES:

- Diagram shown for input Control Enable-LOW and input Control Disable-HIGH
- Pulse Generator for All Pulses: Rate  $\leq 1.0\text{MHz}$ ;  $t_f \leq 2.5\text{ns}$ ;  $t_r \leq 2.5\text{ns}$

**ORDERING INFORMATION**



2572 drw 09